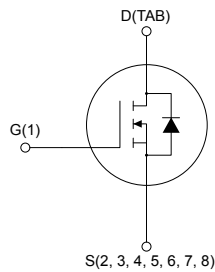
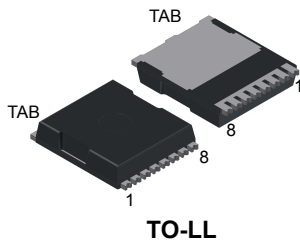


N-channel 60 V, 0.85 mΩ max., 545 A STripFET F7 Power MOSFET in a TO-LL package



G1D1TABSS2345678

Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STO450N6F7	60 V	0.85 mΩ	545 A

- Among the lowest $R_{DS(on)}$ on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Application

- Switching applications

Description

This N-channel Power MOSFET utilizes STripFET F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.



Product status link

[STO450N6F7](#)

Product summary

Order code	STO450N6F7
Marking	450N6F7
Package	TO-LL
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings (at $T_C = 25\text{ °C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	60	V
V_{GS}	Gate-source voltage	± 20	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25\text{ °C}^{(2)}$	545	A
	Drain current (continuous) at $T_C = 100\text{ °C}^{(2)}$	385	
	Drain current (continuous) at $T_C = 25\text{ °C}^{(3)}$	300	
$I_{DM}^{(1)(2)(4)}$	Drain current (pulsed), $t_P = 10\text{ }\mu\text{s}$	2180	A
P_{TOT}	Total power dissipation at $T_C = 25\text{ °C}$	454	W
I_{AS}	Single pulse avalanche current (pulse width limited by maximum junction temperature)	90	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ °C}$, $I_D = 90\text{ A}$, $R_{Gmin} = 25\text{ }\Omega$)	1772	mJ
T_J	Operating junction temperature range	-55 to 175	$^{\circ}\text{C}$
T_{stg}	Storage temperature range		$^{\circ}\text{C}$

1. Specified by design, not tested in production.
2. This is the theoretical current value only related to the silicon.
3. This current value is limited by package.
4. Pulse width is limited by safe operating area.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thJA}^{(1)}$	Thermal resistance, junction-to-ambient (on 2s2p FR-4 board vertical in still area)	11.7	$^{\circ}\text{C/W}$
$R_{thJC}^{(2)}$	Thermal resistance, junction-to-case	0.33	$^{\circ}\text{C/W}$

1. Measured on 4 layer PCB according to Jedec 51.2 in natural convection (still air).
2. Measured according to Jedec 51.14.

2 Electrical characteristics

$T_J = 25\text{ }^{\circ}\text{C}$ unless otherwise specified.

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	60			V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 60\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
		$V_{DS} = 60\text{ V}$, $V_{GS} = 0\text{ V}$, $T_J = 125\text{ }^{\circ}\text{C}^{(1)}$			100	
I_{GSS}	Gate-body leakage current	$V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	2		4	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$, $I_D = 90\text{ A}$		0.75	0.85	m Ω
$R_G^{(1)}$	Gate resistance			1.2		Ω

1. Specified by design and evaluated by characterization, not tested in production.

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}^{(1)}$	Input capacitance	$V_{DS} = 30\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0\text{ V}$	-	16500	-	pF
$C_{oss}^{(1)}$	Output capacitance		-	7500	-	pF
$C_{rss}^{(1)}$	Reverse transfer capacitance		-	400	-	pF
$Q_g^{(1)}$	Total gate charge	$V_{DD} = 30\text{ V}$, $I_D = 90\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$	-	300	-	nC
$Q_{gs}^{(1)}$	Gate-source charge		-	80	-	nC
$Q_{gd}^{(1)}$	Gate-drain charge		-	95	-	nC
$Q_{g(sync)}$	Total gate charge, sync. MOSFET	$I_D = 90\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$	-	220	-	nC
Q_{oss}	Output charge	$V_{DD} = 30\text{ V}$, $V_{GS} = 0\text{ V}$	-	340	-	nC

1. Specified by design and evaluated by characterization, not tested in production.

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}^{(1)}$	Turn-on delay time	$V_{DD} = 30\text{ V}$, $I_D = 90\text{ A}$, $R_G = 4.7\text{ }\Omega$, $V_{GS} = 10\text{ V}$	-	55	-	ns
$t_r^{(1)}$	Rise time		-	100	-	ns
$t_{d(off)}^{(1)}$	Turn-off delay time		-	140	-	ns
$t_f^{(1)}$	Fall time		-	90	-	ns

1. Specified by design and evaluated by characterization, not tested in production.

Table 6. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)(2)}$	Forward on current (continuous)	$T_C = 25\text{ }^{\circ}\text{C}$	-	-	286	A
V_{SD}	Forward on voltage	$I_{SD} = 90\text{ A}$, $V_{GS} = 0\text{ V}$	-	-	1.2	V
$t_{rr}^{(1)}$	Reverse recovery time	$I_D = 90\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 48\text{ V}$	-	95	-	ns
$Q_{rr}^{(1)}$	Reverse recovery charge		-	175	-	nC
$I_{RRM}^{(1)}$	Reverse recovery current		-	3.8	-	A

1. Specified by design and evaluated by characterization, not tested in production.
2. This is the theoretical current value only related to the silicon.

2.1 Electrical characteristics (curves)

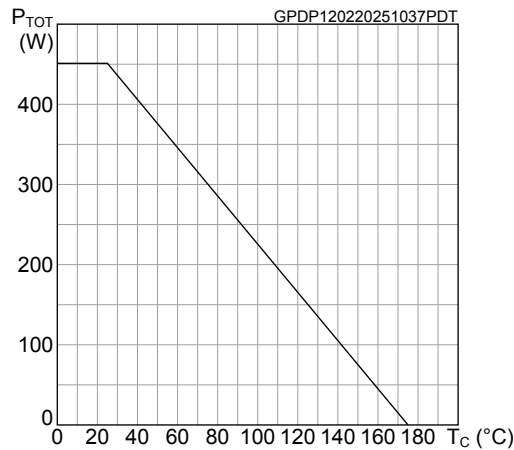
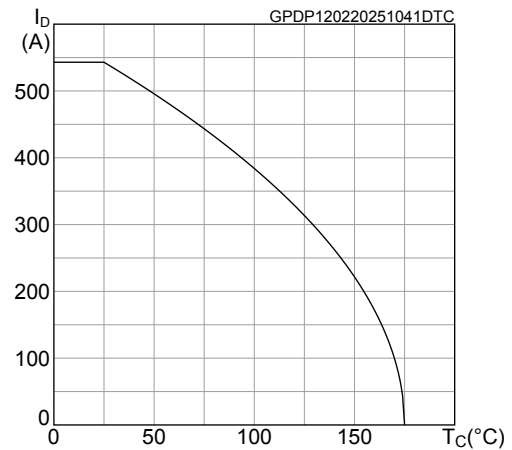
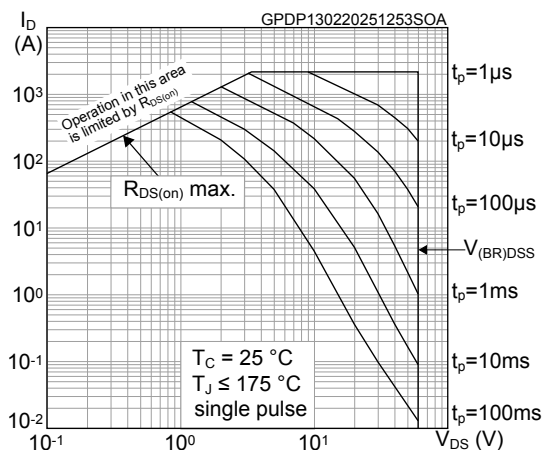
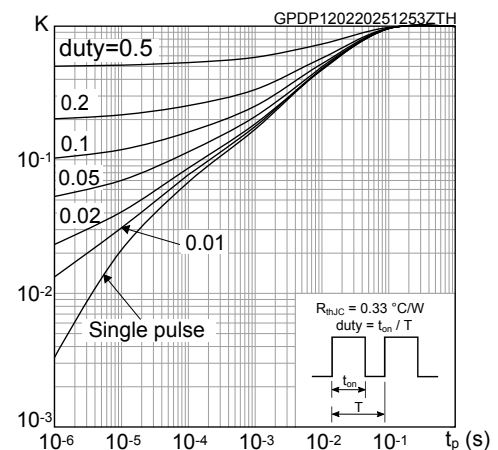
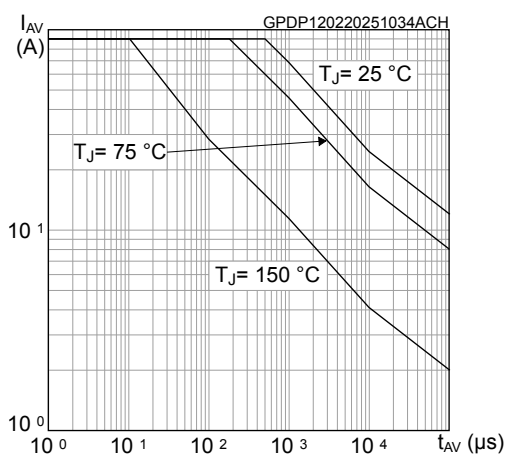
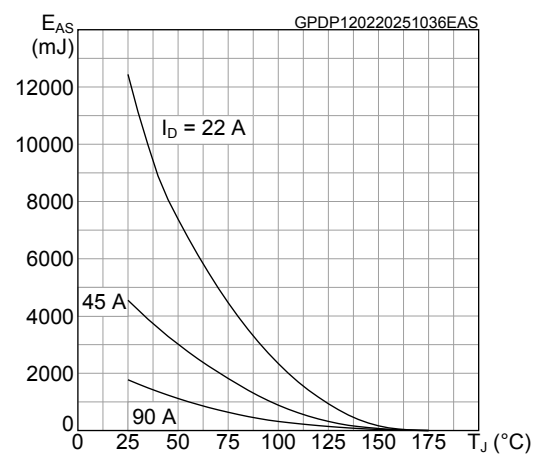
Figure 1. Total power dissipation

Figure 2. Drain current vs case temperature

Figure 3. Safe operating area

Figure 4. Normalized transient thermal impedance

Figure 5. Avalanche characteristics

Figure 6. Avalanche energy


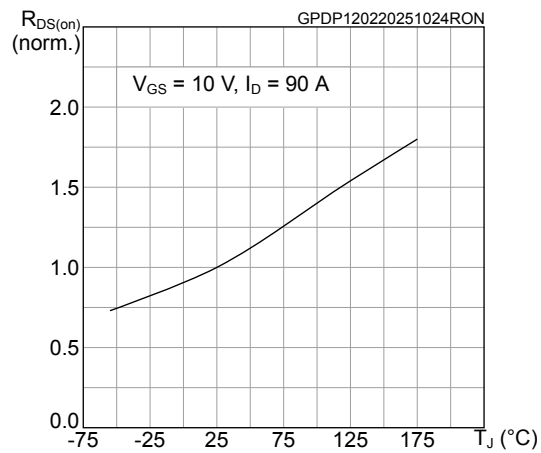
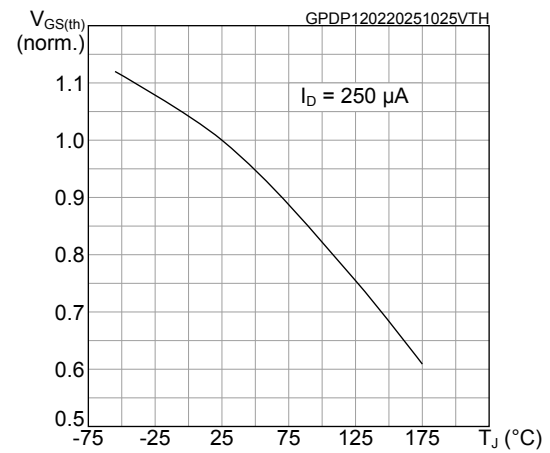
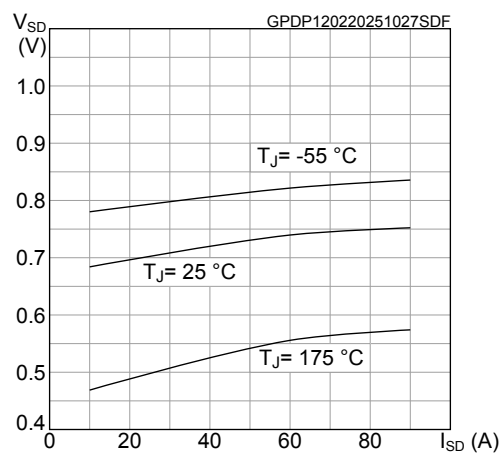
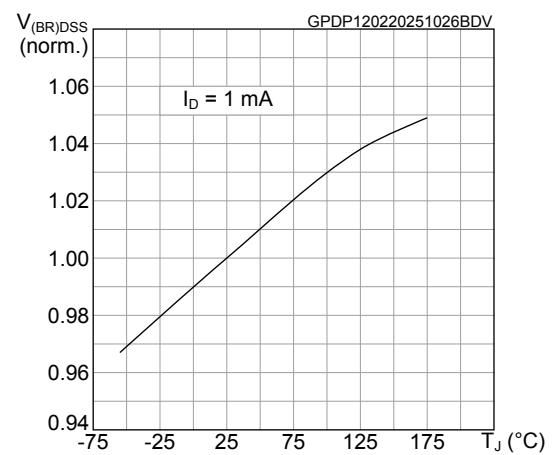
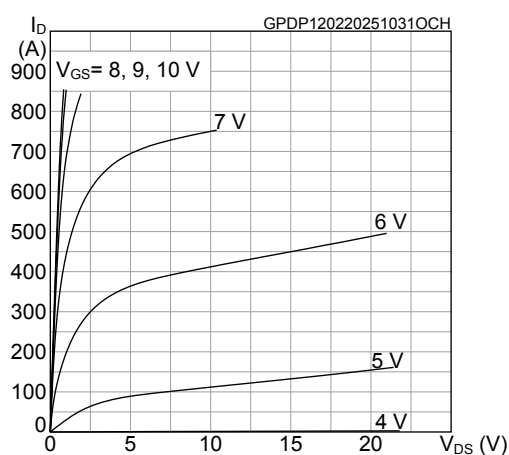
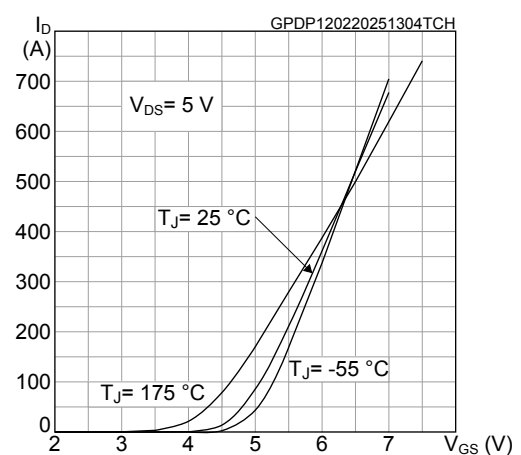
Figure 7. Normalized on-resistance vs temperature

Figure 8. Normalized gate threshold vs temperature

Figure 9. Typical reverse diode forward characteristics

Figure 10. Normalized breakdown voltage vs temperature

Figure 11. Typical output characteristics

Figure 12. Typical transfer characteristics


Figure 13. Typical drain-source on-resistance

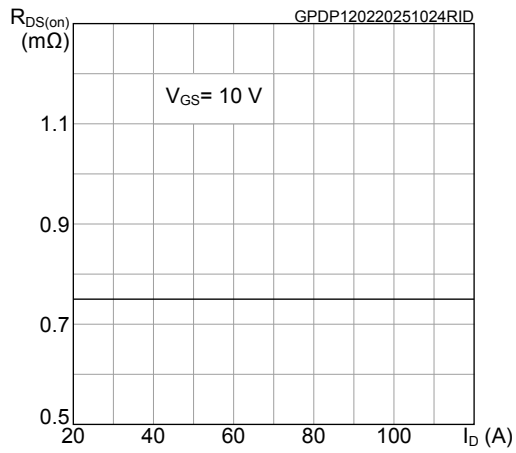


Figure 14. Typical on-resistance vs gate-source voltage

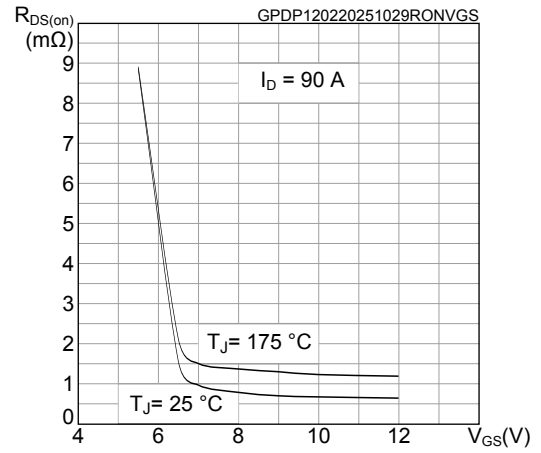


Figure 15. Typical gate charge characteristics

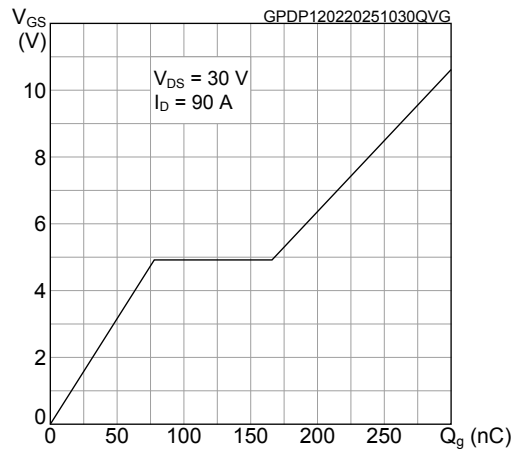
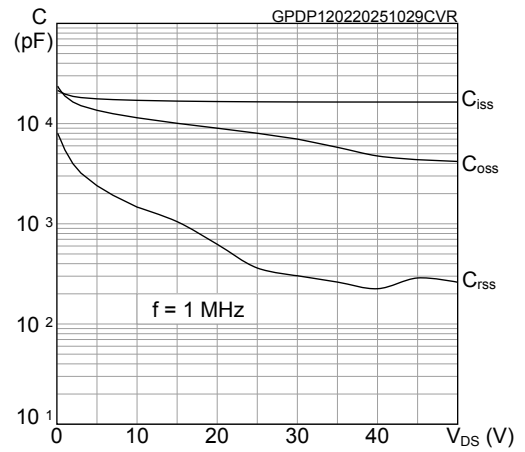


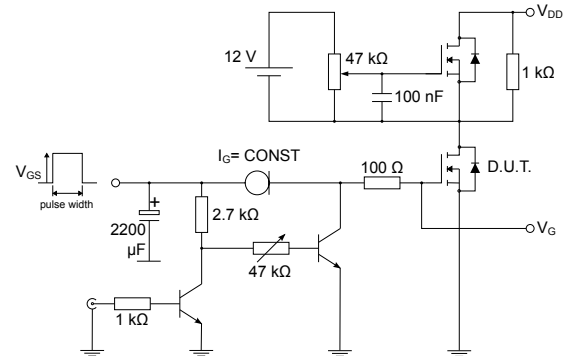
Figure 16. Typical capacitance characteristics



3 Test circuits

Figure 17. Test circuit for resistive load switching times


AM01468v1

Figure 18. Test circuit for gate charge behavior


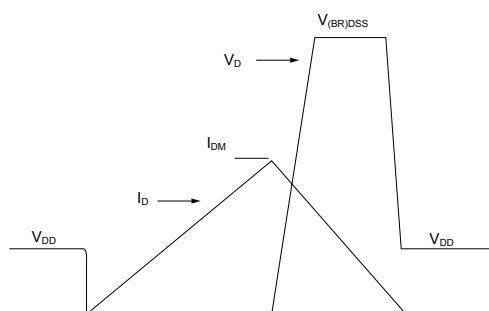
AM01469v1

Figure 19. Test circuit for inductive load switching and diode recovery times

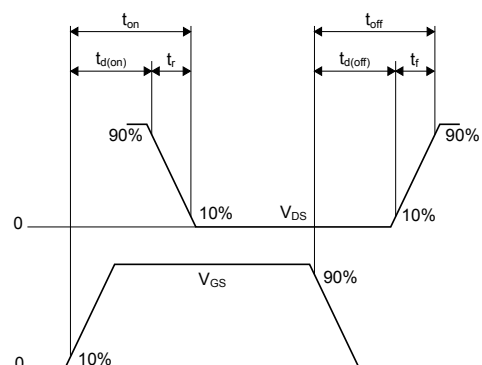

AM01470v1

Figure 20. Unclamped inductive load test circuit


AM01471v1

Figure 21. Unclamped inductive waveform


AM01472v1

Figure 22. Switching time waveform


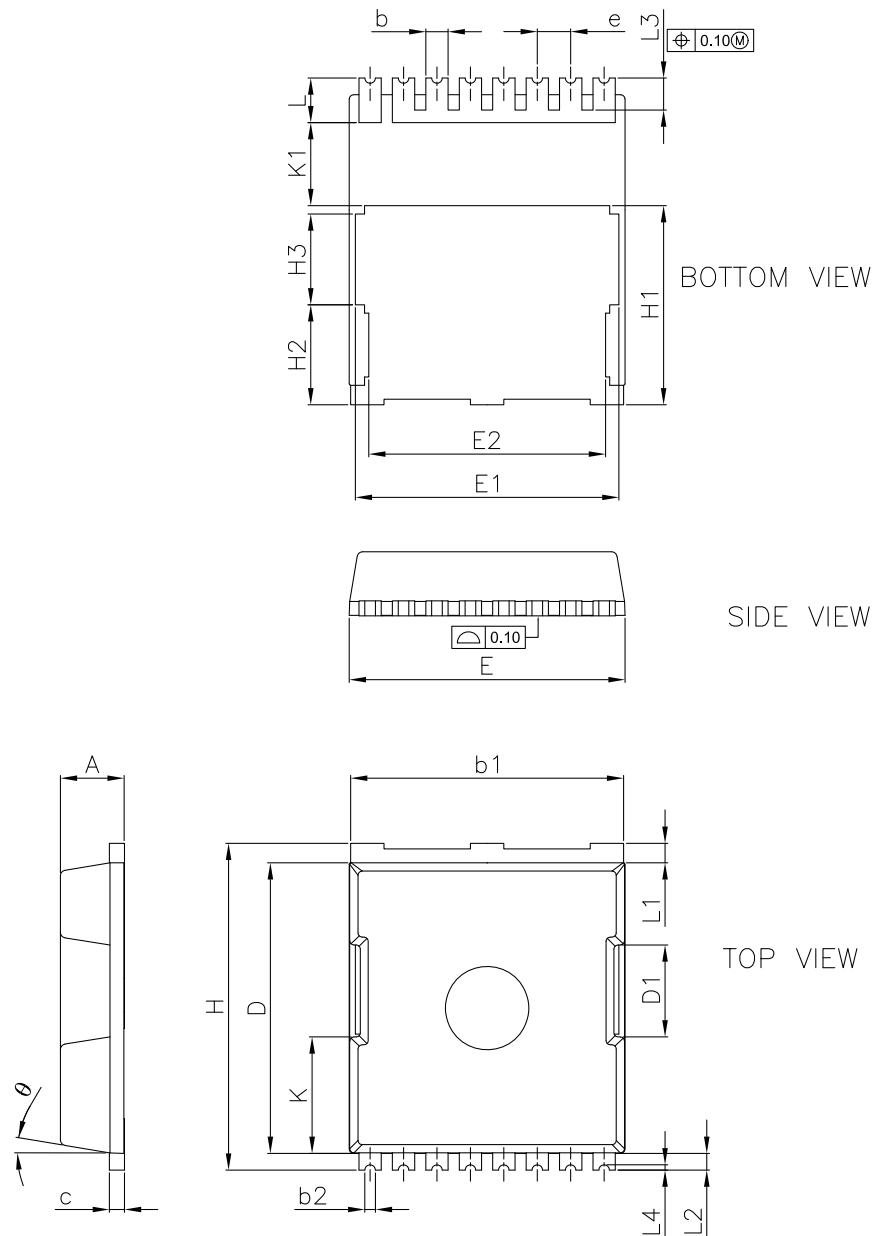
AM01473v1

4 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-LL package information

Figure 23. TO-LL package outline

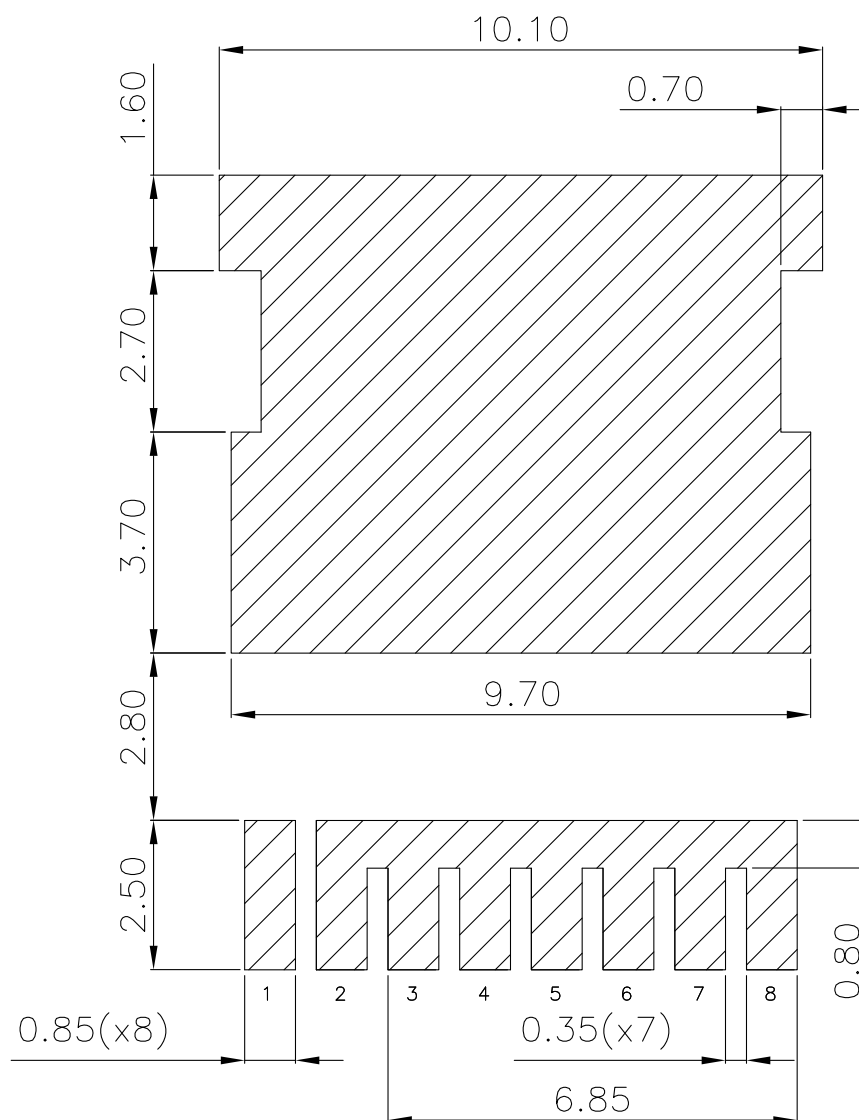


DM00276569_7

Table 7. TO-LL package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.40
b	0.60	0.80	0.90
b1	9.70	9.80	9.90
b2	0.20		0.50
c	0.40	0.50	0.60
D	10.28	10.43	10.58
D1	3.15	3.30	3.45
E	9.70	9.90	10.10
E1	9.31	9.46	9.61
E2	8.35	8.50	8.65
e	1.10	1.20	1.30
H	11.48	11.73	11.88
H1	7.00	7.15	7.30
H2	3.34	3.59	3.84
H3	3.11	3.26	3.41
K	4.03	4.18	4.33
K1	2.70		
L	1.45	1.60	1.75
L1	0.55	0.70	0.85
L2	0.45	0.60	0.75
L3	1.00	1.15	1.30
L4	0.05		0.40

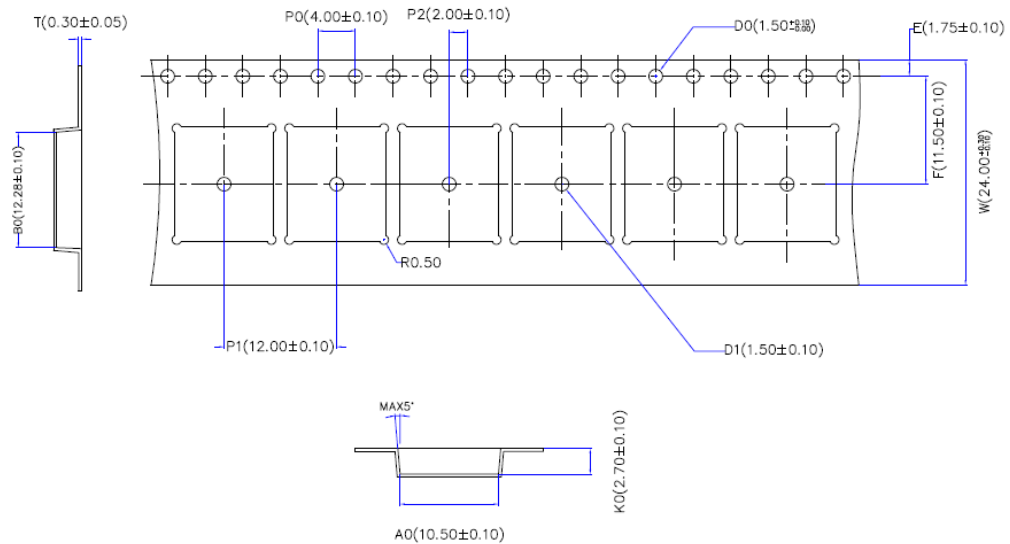
Figure 24. TO-LL recommended footprint (dimensions are in mm)



DM00276569_7_FP

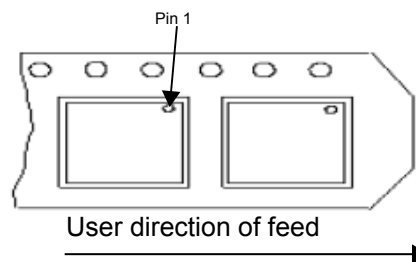
4.2 TO-LL packing information

Figure 25. Carrier tape outline and dimensions



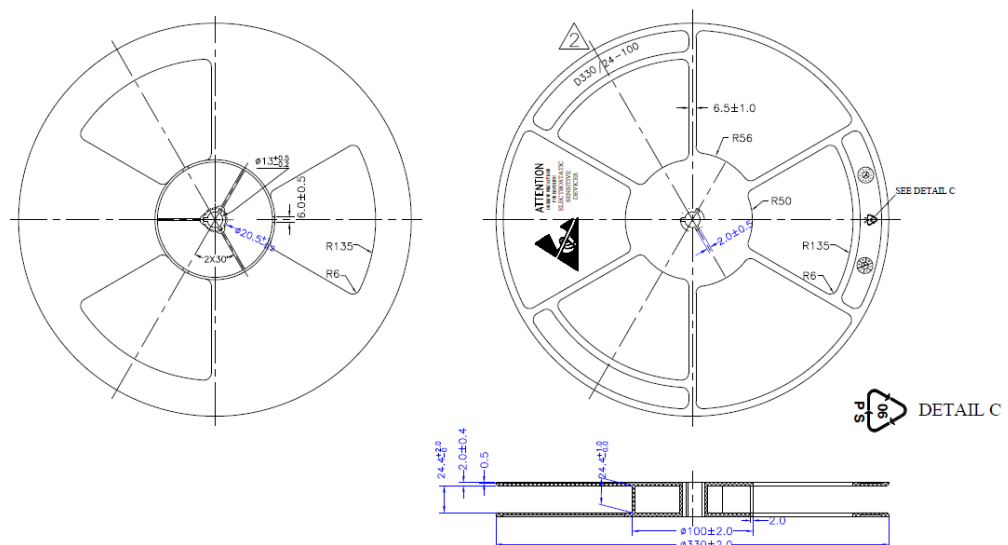
Carrier_DM00282027_5

Figure 26. TO-LL orientation in carrier tape



orientation_carrier_tape_0031932_65

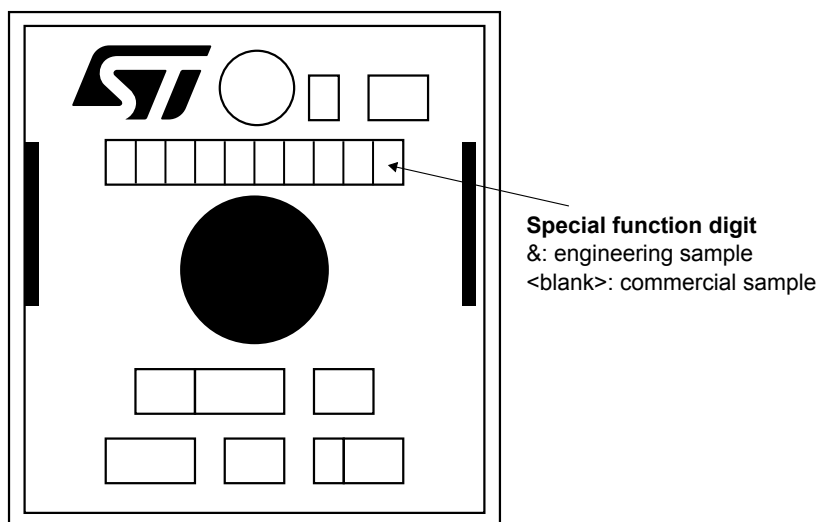
Figure 27. Reel outline and dimensions



Reel_DM00282027_5

4.3 TO-LL marking information

Figure 28. TO-LL marking information



Note: *Engineering Samples: these samples can be clearly identified by a dedicated special symbol in the marking of each unit. These samples are intended to be used for electrical compatibility evaluation only; usage for any other purpose may be agreed only upon written authorization by ST. ST is not liable for any customer usage in production and/or in reliability qualification trials.*

Commercial Samples: fully qualified parts from ST standard production with no usage restrictions.

Revision history

Table 8. Document revision history

Date	Version	Changes
02-Aug-2024	1	Initial release.
17-Mar-2025	2	Updated <i>Section 1: Electrical ratings</i> and <i>Section 2: Electrical characteristics</i> . Added <i>Section 2.1: Electrical characteristics (curves)</i> . Updated <i>Section 4.2: TO-LL packing information</i> . Minor text changes.
07-Apr-2025	3	Updated Section 2.1: Electrical characteristics (curves) . Minor text changes.

Contents

1	Electrical ratings	2
2	Electrical characteristics	3
2.1	Electrical characteristics (curves)	5
3	Test circuits	8
4	Package information	9
4.1	TO-LL package information	9
4.2	TO-LL packing information	12
4.3	TO-LL marking information	13
	Revision history	14

IMPORTANT NOTICE – READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgment.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2025 STMicroelectronics – All rights reserved